


<b>Search Notes</b>  	<b>Application/Control No.</b>  10751176	<b>Applicant(s)/Patent Under Reexamination</b>  GEIER ET AL.
	<b>Examiner</b>  Flores, Leon	<b>Art Unit</b>  2635

SEARCHED			
Class	Subclass	Date	Examiner
375	130,134, 137, 142, 145, 150, 316, 343, 344, 355	12/06/2006	LF
342	357.12	12/06/2006	LF

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE Vu Le in regards to the patentability of the claims	12/11/2006	LF
Consulted with Primary Lin Ye in regards to claim 1.	12/06/2006	LF
Checked for double patenting	12/07/2006	LF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner